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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/602,045	HANNA, MICHELLE M.	
Examiner	Art Unit	
Young J. Kim	1637	

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED				
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed text-search strategy	11/6/2006	YJK
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